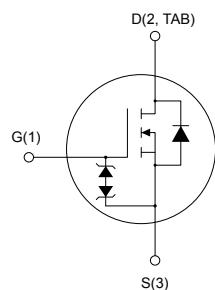
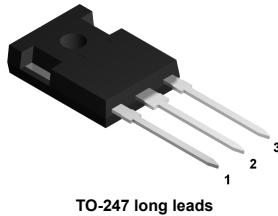


## N-channel 600 V, 45 mΩ typ., 52 A MDmesh M6 Power MOSFET in a TO-247 long leads package



AM01476v1\_tab

### Features

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STWA67N60M6	600 V	49 mΩ	52 A

- Reduced switching losses
- Lower R<sub>DS(on)</sub> per area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications
- LLC converters
- Boost PFC converters

### Description

The new MDmesh M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent R<sub>DS(on)</sub> per area improvement with one of the most effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.



#### Maturity status link

STWA67N60M6

#### Device summary

Order code	STWA67N60M6
Marking	67N60M6
Package	TO-247 long leads
Packing	Tube

## 1 Electrical ratings

**Table 1.** Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	52	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	33	A
$I_{DM}$ <sup>(1)</sup>	Drain current (pulsed)	200	A
$P_{TOT}$	Total power dissipation at $T_C = 25^\circ\text{C}$	330	W
$dv/dt$ <sup>(2)</sup>	Peak diode recovery voltage slope	15	V/ns
$dv/dt$ <sup>(3)</sup>	MOSFET dv/dt ruggedness	100	
$T_{stg}$	Storage temperature range	-55 to 150	$^\circ\text{C}$
$T_j$	Operating junction temperature range		

1. Pulse width is limited by safe operating area.
2.  $I_{SD} \leq 52 \text{ A}$ ,  $di/dt \leq 400 \text{ A}/\mu\text{s}$ ,  $V_{DS(\text{peak})} < V_{(BR)DSS}$ ,  $V_{DD} = 400 \text{ V}$
3.  $V_{DS} \leq 480 \text{ V}$

**Table 2.** Thermal data

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance, junction-to-case	0.38	$^\circ\text{C}/\text{W}$
$R_{thJA}$	Thermal resistance, junction-to-ambient	50	$^\circ\text{C}/\text{W}$

**Table 3.** Avalanche characteristics

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	6	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ )	900	mJ

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 4.** On /off-states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
$I_{\text{DSS}}$	Zero-gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$		1		$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_C = 125^\circ\text{C}$ (1)			100	
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 5$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3.25	4	4.75	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 26 \text{ A}$		45	49	$\text{m}\Omega$

1. Specified by design, not tested in production.

**Table 5.** Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}$	-	3400	-	pF
$C_{oss}$	Output capacitance		-	280	-	pF
$C_{rss}$	Reverse transfer capacitance		-	2	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to } 480 \text{ V}$	-	520	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	1.4	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 52 \text{ A}$	-	72.5	-	nC
$Q_{gs}$	Gate-source charge	$V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	24.5	-	nC
$Q_{gd}$	Gate-drain charge		-	28.5	-	nC

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6.** Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 26 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	24.5	-	ns
$t_r$	Rise time		-	35	-	ns
$t_{d(off)}$	Turn-off delay time		-	72	-	ns
$t_f$	Fall time	(see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	10.5	-	ns

**Table 7. Source-drain diode**

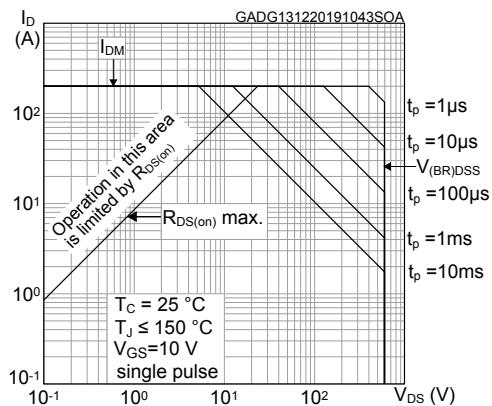
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		52	A
$I_{SDM}$ <sup>(1)</sup>	Source-drain current (pulsed)		-		200	A
$V_{SD}$ <sup>(2)</sup>	Forward on voltage	$V_{GS} = 0 \text{ V}$ , $I_{SD} = 52 \text{ A}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 52 \text{ A}$ , $di/dt = 100 \text{ A}/\mu\text{s}$ ,	-	348		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 60 \text{ V}$ (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	5.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	32		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 52 \text{ A}$ , $di/dt = 100 \text{ A}/\mu\text{s}$ ,	-	484		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 60 \text{ V}$ , $T_j = 150^\circ\text{C}$	-	10.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	44		A

1. Pulse width is limited by safe operating area.

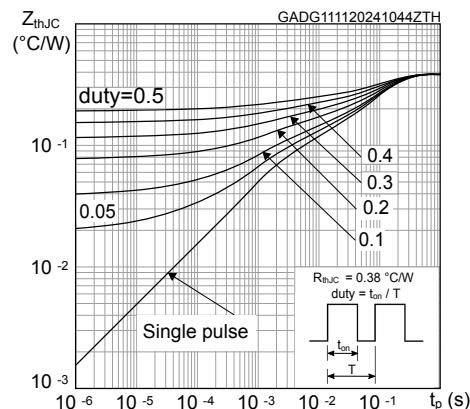
2. Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

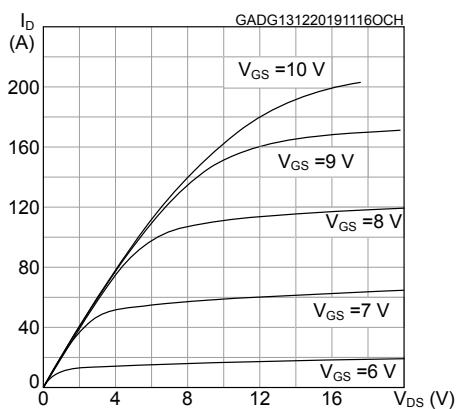
**Figure 1. Safe operating area**



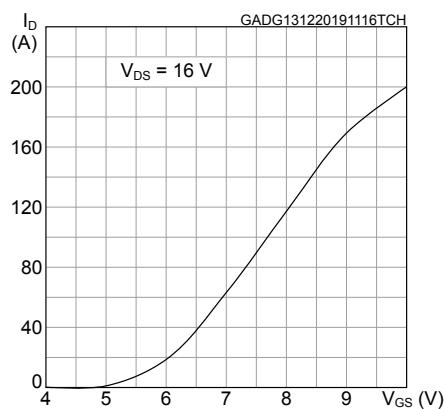
**Figure 2. Maximum transient thermal impedance**



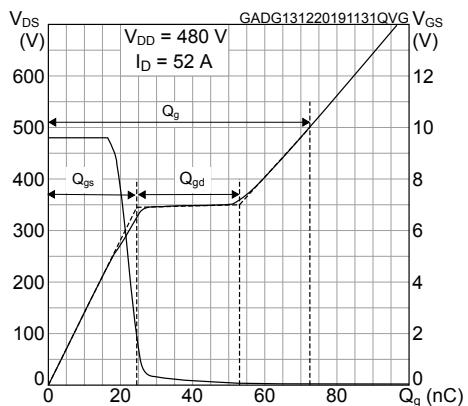
**Figure 3. Typical output characteristics**



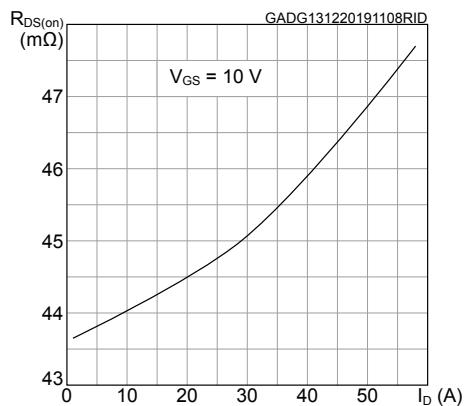
**Figure 4. Typical transfer characteristics**

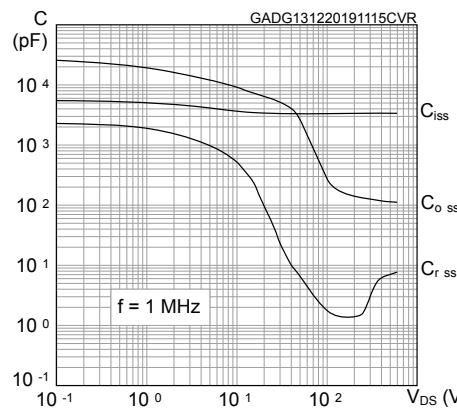
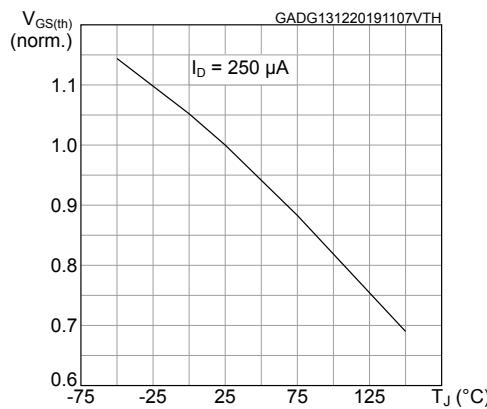
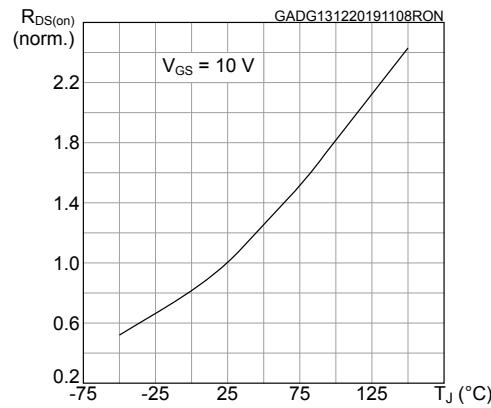
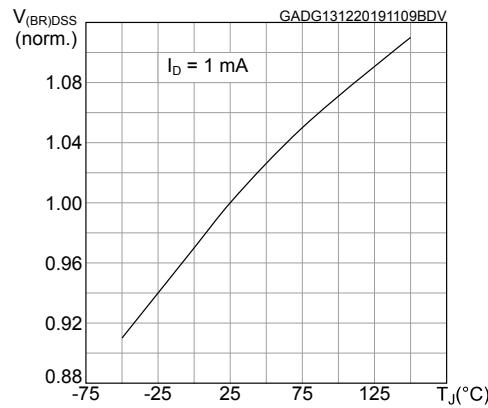
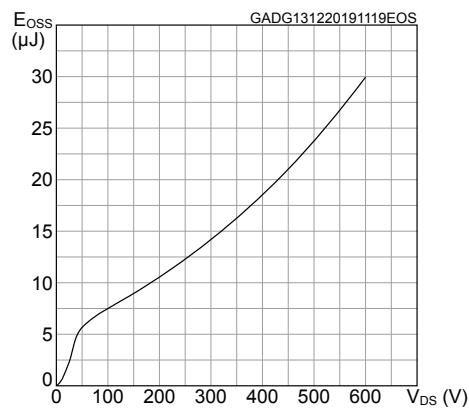
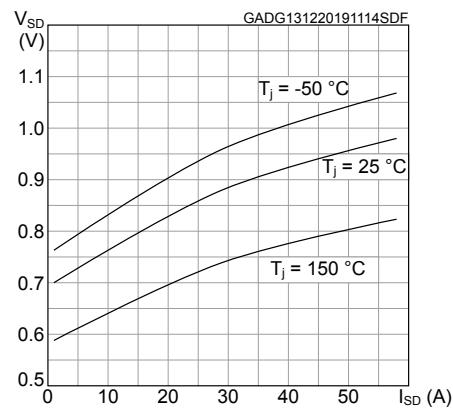


**Figure 5. Typical gate charge characteristics**



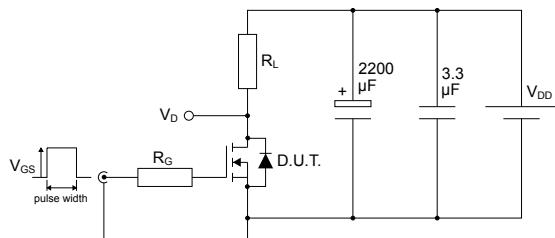
**Figure 6. Typical drain-source on-resistance**



**Figure 7. Typical capacitance characteristics**

**Figure 8. Normalized gate threshold vs. temperature**

**Figure 9. Normalized on-resistance vs. temperature**

**Figure 10. Normalized breakdown voltage vs temperature**

**Figure 11. Typical output capacitance stored energy**

**Figure 12. Typical reverse diode forward characteristics**


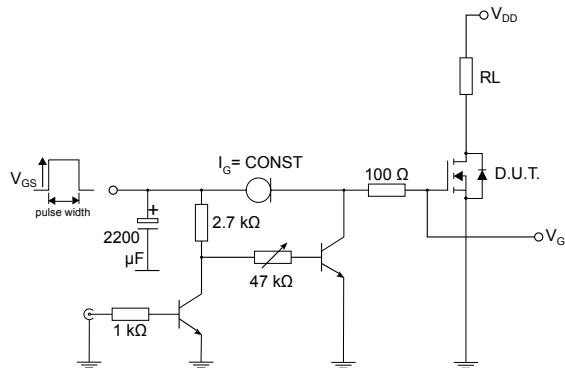
### 3 Test circuits

**Figure 13.** Test circuit for resistive load switching times



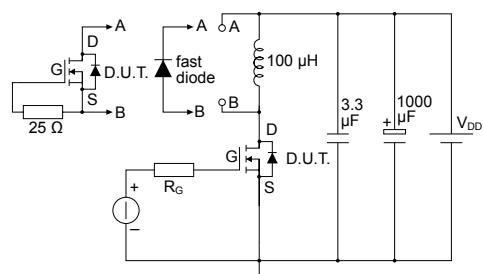
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**Figure 14.** Test circuit for gate charge behavior



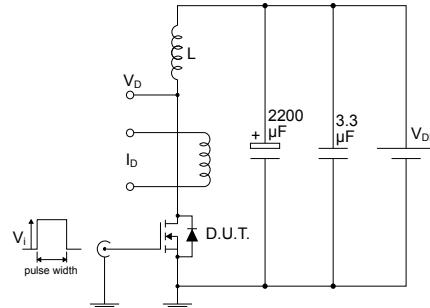
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**Figure 15.** Test circuit for inductive load switching and diode recovery times



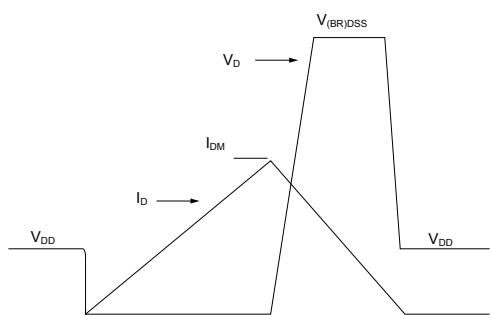
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**Figure 16.** Unclamped inductive load test circuit



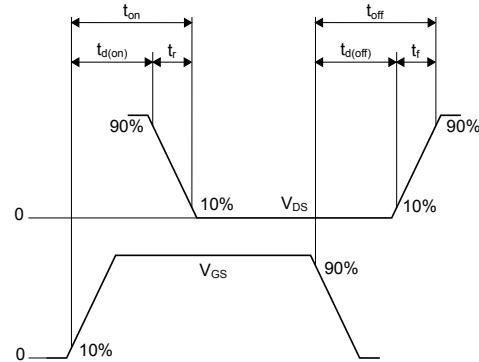
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**Figure 17.** Unclamped inductive waveform



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**Figure 18.** Switching time waveform



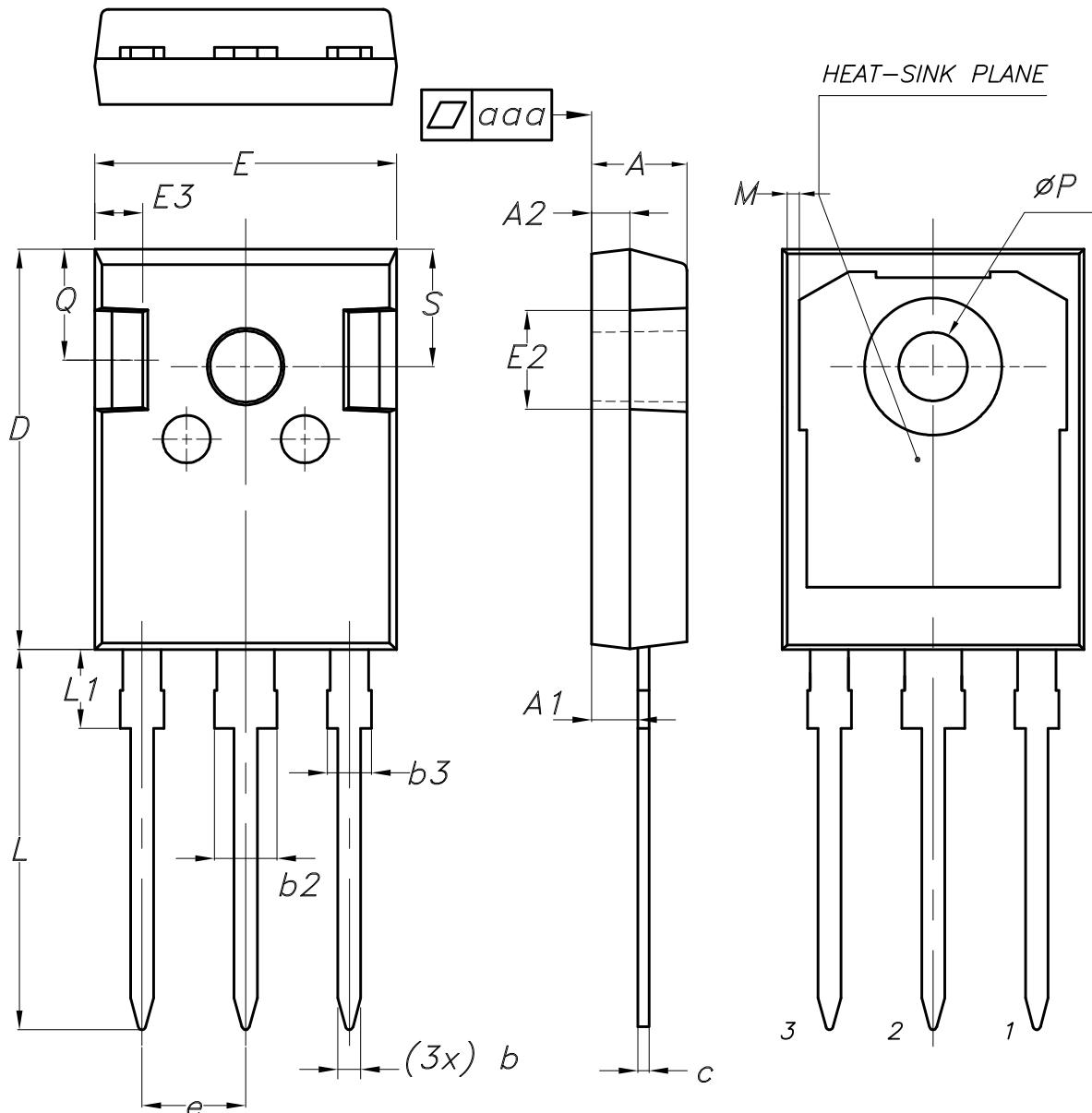
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## 4 Package information

To meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 TO-247 long leads package information

Figure 19. TO-247 long leads package outline



BACK VIEW

8463846\_5

**Table 8. TO-247 long leads package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16		1.26
b2			3.25
b3			2.25
c	0.59		0.66
D	20.90	21.00	21.10
E	15.70	15.80	15.90
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
e	5.34	5.44	5.54
L	19.80	19.92	20.10
L1			4.30
M	0.35		0.95
P	3.50	3.60	3.70
Q	5.60		6.00
S	6.05	6.15	6.25
aaa		0.04	0.10

## Revision history

**Table 9. Document revision history**

Date	Revision	Changes
18-Dec-2019	1	First release.
28-Feb-2025	2	Updated <a href="#">Section 4.1</a> : TO-247 long leads package information. Minor text changes.

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